

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. <i>205109 US 20 DIV</i>		SERIAL NO. <i>new appl.</i>	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT		Paul ENQUIST			
		FILING DATE <i>Herewith</i>		GROUP <i>not yet assigned</i>			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
NW	AA	5,387,807	02/07/95	Burhan BAYRAKTAROGLU			
NW	AB	5,943,577	08/24/99	Walter CONTRATA, et al.			
NJ	AC	5,856,209	01/05/99	Kenji IMANISHI			
NJ	AD	5,684,308	11/04/97	Michael L. LOVEJOY, et al.			
NJ	AE	5,648,294	07/15/97	Burhan BAYRAKTAROGLU			
NJ	AF	5,552,617	09/03/96	Darrell G. HILL, et al.			
NJ	AG	5,512,496	04/30/96	Hin F. CHAU, et al.			
NJ	AH	5,468,658	11/21/95	Burhan BAYRAKTAROGLU			
NJ	AI	5,391,504	02/21/95	Darrell HILL, et al.			
NJ	AJ	5,249,074	09/28/93	Peter J. TOPHAM			
NJ	AK	5,239,550	08/24/93	Faquir C. JAIN			
NJ	AL	5,037,769	08/06/91	Masanori INADA, et al.			
NJ	AM	4,824,805	04/25/89	Yasutomo KAJIKAWA			
NJ	AN	4,751,201	06/14/88	Richard N. NOTTENBURG, et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
AO							
AP							
AQ							
AR							
AS							
AT							
AU							
AV							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
Examiner <i>NJm J NJ</i>					Date Considered <i>5-14-92</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449  
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PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

205109US20 DIV

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LIST OF REFERENCES CITED BY APPLICANT  
(Use Several Sheets if Necessary)

APPLICANT PAUL ENQUIST

FILING DATE

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GROUP

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	AA						
	AB						
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	AK						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO
	AL				
	AM				
	AN				
	AO				
	AP				

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ	Submicron Lateral Scaling of Vertical-Transport Devices: Transferred-Substrate Bipolar Transistors and Schottky-Collector Tunnel Diodes; M. Rodwell, et al.; Invited Paper, 1997 OSA Ultrafast Electronics and Optoelectronics Conference
	AR	A 277-GHz $f_{max}$ Transferred-Substrate Heterojunction Bipolar Transistor; B. Agarwal, et al.; IEEE Electron Device Letters, Vol. 18, No. 5, May 1997, pgs. 228-231
	AS	Transferred Substrate Schottky-Collector Heterojunction Bipolar Transistors: First Results and Scaling Laws for High $f_{max}$ ; U. Bhattacharya, et al.; IEEE Electron Device Letters, Vol. 16, No. 8, August 1995, pgs. 357, 359
	AT	$A > 400$ GHz $f_{max}$ Transferred-Substrate HBT Integrated Circuit Technology; R. Pullela, et al.; DRC 1997
	AU	Deep Submicron Transferred-Substrate Heterojunction Bipolar Transistors; Q. Lee, et al.; DRC 1998
	AV	170 GHz Transferred-Substrate Heterojunction Bipolar Transistor; U. Bhattacharya, et al.; Electronics Letters, 18th July 1996, Vol. 32, No. 15, pgs. 1405-6
	AW	Transferred Substrate Heterojunction Bipolar Transistors; Dissertation by U. Bhattacharya, Nov. 27, 1996
	AX	Digital Integrated Circuits in the Transferred-Substrate HBT Technology; Dissertation by R. Pullela, June 1998

EXAMINER

N/Jan ✓ NV

DATE CONSIDERED

5-14-02

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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<u>NJ</u>	AA	5,318,916	06/07/94	ENQUIST ET AL.	—	—	
	AB						
	AC						
	AD						
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	AG						
	AH						
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	AL						
	AM						
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	AV						
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	AW						
	AX						
	AY						
	AZ						
Examiner <u>Wjm ✓</u>					Date Considered <u>5-14-94</u>		

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